

# Ryo Kishida

## List of Publications by Year in descending order

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Version: 2024-02-01

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#	ARTICLE	IF	CITATIONS
1	Extracting Voltage Dependence of BTI-induced Degradation Without Temporal Factors by Using BTI-Sensitive and BTI-Insensitive Ring Oscillators. IEEE Transactions on Semiconductor Manufacturing, 2020, 33, 174-179.	1.7	11
2	Bias Temperature Instability Depending on Body Bias through Buried Oxide (BOX) Layer in a 65 nm Fully-Depleted Silicon-On-Insulator Process. , 2021, , .		1
3	An Aging Degradation Suppression Scheme at Constant Performance by Controlling Supply Voltage and Body Bias in a 65 nm Fully-Depleted Silicon-On-Insulator Process. , 2022, , .		1